

ABSTRACT OF THE DISCLOSURE

There is disclosed a semiconductor integrated circuit device capable of eliminating an influence of a power voltage drop generated in a circuit disposed in the semiconductor integrated circuit device to inhibit an operation defect or an operation speed decrease of the circuit. In a semiconductor integrated circuit device 10 including a power wiring 18 connected to a power supply (Vdd) via a power terminal 12, a ground wiring 20 connected to a ground (0 V) via a ground terminal 14, and a plurality of circuits 301 to 30f connected in parallel with one another between the power wiring 18 and the ground wiring 20, a negative power terminal 16 connected to a negative power supply (-Vdd) is disposed, and a current source 22 is disposed as a current generating section between the negative power terminal 16 and a node Gf on a ground wiring 20 side of the f-th circuit 30f disposed in a region most distant from the ground.